# **Electronic Supplementary Materials (ESI)**

# Ferroelectric properties, narrow band gap and ultra-large reversible entropy change in a novel nonlinear ionic chromium (VI) compound

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#### **Experimental section**

#### Synthesis

All chemicals and reagents were purchased directly from the chemical reagent company and used directly without further purification. The synthesis of compound **1** is mainly carried out in two steps: the first step is the synthesis of precursor: measured 50 mL of triethylamine and poured into a round-necked flask, then measured 100 mL of dichloromethane as the solvent and the reactant to pour into the flask, heated and stirred in a water bath at a constant temperature of 70 °C for 72 hours, filtered and left the clear liquid to volatilize into a white solid, and finally dried it to become the precursor chloromethyl-triethylammonium chloride; in the second step, weighed the precursor (0.186 g, 1 mmol) and dissolved it in 15 mL of deionized water, then weighed chromium trioxide (0.099 g, 1 mmol) and poured into the solution, stirred for 45 min, filtered to obtain an orange-yellow solution, and finally volatilized at room temperature for about 2 weeks to obtain an orange-yellow block crystals (yield 36 %). The purity of compound **1** was well confirmed by the infrared spectrum (IR) (**Fig. S1**) and powder X-ray diffraction (PXRD) pattern (**Fig. S2**). Elemental analysis calcd. for compound **1**: 3740 (w), 3410 (w), 2987 (w), 2360 (w), 1639 (w), 1469 (m), 1153 (m), 943 (s), 803 (m), 426 (m).

#### Differential Scanning Calorimetry (DSC)

DSC tests were performed on a Perkin-Elmer Diamond DSC Instrument. The compound **1** (7.2 mg) using powder samples were placed in aluminum crucibles, and were tested in a temperature range of 315 K-370 K under a nitrogen atmosphere at a heating/cooling rate of 10 K/min.

#### Thermogravimetric Analysis (TGA)

TGA measurements of compound **1** (2 mg) were carried out on a TA-Instrument STD2960 system at a heating rate of 10 K/min under a nitrogen atmosphere in the temperature range of 310 K-1050 K. During the heating process, the peak of the DTA pattern at 340.5 K was an endothermic peak, while the exothermic decomposition peak was around 443 K. The arrow marked in the figure is the direction of heat release.

#### X-Ray Single-Crystal Crystallography

The X-ray single crystal diffraction data of compound **1** was collected on a Rigaku Oxford Diffraction with Mo K $\alpha$  radiation ( $\lambda = 0.71073$  Å) at the room temperature. The data was corrected for  $L_p$  and absorption effects. The structure was solved by direct methods and refined by the full-matrix methods based on F<sup>2</sup> by using the SHELXLTL software package. All non-hydrogen atoms were refined anisotropically, and all hydrogen atoms were generated geometrically and refined by using a "riding" model with  $U_{iso} = 1.2 U_{eq}$  (C). The occupancy rate of the disordered part was refined with free variables. The crystallographic data and structural refinement details of compound **1** are shown in **Table S1**. The CCDC (Cambridge Crystallographic Data Centre) of compound **1** is No.: 2091371. **Powder X-Ray Diffraction (PXRD) and Elemental Analysis** 

Variable-Temperature PXRD measurements of compound **1** on a PANalytical X' Pert PRO X-ray diffractometer were carried out in the temperature range of 300 K-370 K and the diffraction patterns were collected in the range of 2 $\theta$  = 5°-50° with a step size of 0.02°. Elemental analysis (C, H, N) of compound **1** was performed by elementar vario EL cube organic element analyzer, Germany.

#### **Dielectric Constant Measurements**

For dielectric experiments, the pressed powder pellets (0.2 mm thick and 3 mm<sup>2</sup> in area) of compound **1** were sandwiched between two parallel copper electrodes with silver-conducting glue to be used for dielectric measurements. The temperature-dependent dielectric constants tests were carried out using the sample on a TH2828A instrument between 303 K-355 K over the frequency range of 500 Hz to 1 MHz, with an applied electric field of 1 V, controlling heating and cooling rate of 10 K/min.

#### Second Harmonic Generation (SHG) Measurements

The SHG signal tests of powder samples of compound **1**, using an unexpanded laser beam with low divergence (pulsed Nd: YAG at a wavelength of 1064 nm, 5 ns pulse duration, 1.6 MW peak power, 10 Hz repetition rate) were carried out on the Ins1210058, INSTEC Instruments at the room temperature.

#### Solid-State Circular Dichroism (CD) Spectra

The CD spectra for compound **1** were recorded on a Jasco-1500 CD spectropolarimeter at the room temperature in the wavelength range 200 nm-700 nm. The CD spectra were obtained on the resulting complexes as crystals (ca. 0.4 mg) in 100 mg of oven-dried KBr made into disks of 0.3 mm thickness.

#### Ultraviolet-Visible (UV-vis) Spectrometry

The UV-vis absorption spectrum was obtained at room temperature in the wavelength range of 200 nm-700 nm by using a Shimadzu (Tokyo, Japan) UV-2550 spectrophotometer by measuring the powder of compound **1**. Determining the band gap with the variation of Tauc equation:<sup>1</sup>

#### $[hv \cdot F(R_{\infty})]^{1/n} = A(hv - E_g)$

where *h* is the Planck's constant, *v* represents the frequency of vibration, *A* is the proportional constant,  $E_g$  is the band gap and  $F(R_{\infty})$  is Kubelka-Munk equation:  $F(R_{\infty}) = (1-R_{\infty})^2/2R_{\infty}^2$ .

#### **Ferroelectric Property**

The ferroelectric property of single crystal samples of compound **1** were measured by using a standard RT 6000 ferroelectric tester (Radiant Technologies, Albuquerque, USA) at different temperatures after the samples were immersed in insulating oil and dried at the room temperature. And the polarization-electric hysteresis loops were observed by virtual ground mode (the measurement used alternating current and the frequency was 10-60 Hz).



Fig. S1 Infrared (IR) spectra of solid compound 1 at room temperature.



Fig. S2 PXRD (powder x-ray diffraction) measurement comparison with single crystal simulation of compound 1 at room temperature.



**Fig. S3** Temperature dependence of the real parts ( $\epsilon'$ ) of the dielectric constants for compound **1** at selected frequencies (5 kHz, 10 kHz, 100 kHz and 1 MHz).



**Fig. S4** Lebail refinement of PXRD data of compound **1** at 344 K, revealing a unit cell of a = 7.89479 Å, b = 7.89479 Å, c = 12.7266 Å,  $\alpha = 90^\circ$ ,  $\theta = 90^\circ$  and  $\gamma = 120^\circ$ .



Fig. S5 Variable-Temperature PXRD for compound 1 in the temperature range of 300 K-370 K.



Fig. S6 The temperature-dependence of dielectric constant at 1MHz during heating and cooling runs for compound 1.



Fig. S7 The comparison of KDP, SHG response of compound 1 under the same condition.



Fig. S8 The calculation diagram band structures of compound 1.

Table S1. The crystallographic data and structure refin	ements for compound 1 at the room terr	perature.
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[(CH <sub>3</sub> CH <sub>2</sub> ) <sub>3</sub> N(CH <sub>2</sub> Cl)] [CrO <sub>3</sub> Cl]			
298 К			
Formula weight	286.11	Z	4
Crystal system	monoclinic	Density (g/cm <sup>3</sup> )	1.539
Space group	С2	m (mm⁻¹)	1.342
<i>a</i> (Å)	11.8344(6)	F (000)	592.0
b (Å)	7.8851(3)	Data/restraints/parameters	2527/3/173
<i>c</i> (Å)	14.4218(12)	GOF	1.097
α (°)	00	$R_1, wR_2[l \ge 2\sigma(l)]$	$R_1 = 0.0346$
	90		$wR_2 = 0.1007$
β (°) 113.414(5)	112 414(5)	<i>R1, wR2</i> (all data)	$R_1 = 0.0369$
	113.414(5)		$wR_2 = 0.1026$
γ (°)	90	$ riangle  ho_{\textit{max}} /  riangle  ho_{\textit{min}}$ (eÅ-3)	0.31/-0.49
V (ų)	1234.96(14)		

## Calculation of $\Delta S$ and N

In the heating cycle mode  

$$\Delta S_{1} = R \ln N_{1}$$

$$\Delta S_{2} = R \ln N_{2}$$

$$\Delta S_{1} = \int_{T_{2}}^{T_{1}} \frac{Q}{T} dT$$

$$\approx \frac{\Delta H}{T_{c}}$$

$$= \frac{75.65g^{-1}J \times 286.11moI^{-1}g}{340.9K}$$

$$= 63.49J \cdot moI^{-1} \cdot K^{-1}$$

$$N_{I} = \exp(\frac{\Delta S_{1}}{R}) = \exp(\frac{63.49J \cdot moI^{-1} \cdot K^{-1}}{8.314J \cdot moI^{-1} \cdot K^{-1}})$$

$$R_{2} = \exp(\frac{\Delta S_{1}}{R}) = \exp(\frac{63.49J \cdot moI^{-1} \cdot K^{-1}}{8.314J \cdot moI^{-1} \cdot K^{-1}})$$

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### Notes and references

- 1 J. Tauc, Mater. Res. Bull., 1970, **5**, 721-729.
- 2 W. J. Wei, C. Li, L. S. Li, Y. Z. Tang, X. X. Jiang and Z. S Lin, J. Mater. Chem. C, 2019, 7, 11964-11971.